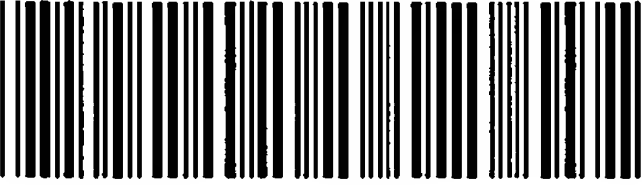






<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/633,434	KIM ET AL.	
	Examiner	Art Unit	
	Hsien-ming Lee	2823	

SEARCHED			
Class	Subclass	Date	Examiner
438	106,107	2/3/2005	LEE <i>Lee</i>
438	123,124		
257	666,668		
257	672,673		
257	676,677		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
438	106,107	2/3/2005	LEE <i>Lee</i>
438	123,124		
257	666,668		
257/672,673,676,677			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST attached (USPAT, USPG, USOCR, EPO, JPO, IBM, Derwent)	2/3/2005	LEE
